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Approved Method Optical and Electrical Measurements of AC-LED Packages and Arrays or Modules

Approved American National Standard
ANSI

ANSI/IES LM-88-18

Approved Method: Optical and Electrical Measurements of AC-LED Packages and Arrays or Modules

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Prepared by the Solid-State Lighting Subcommittee of the

IES Testing Procedures Committee

LM-88-18 Working Group

Yuqin Zong, Technical Coordinator
A. Baker
P. Chou
P. Elizondo
M. Grather
J. Hulett
A. Jackson
J. Jiao
D. Neal
A. Nishida
Y. Ohno

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